



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named  
Inventor : David W. Duquette  
Appln. No. : 09/767,199 ✓  
Filed : January 22, 2001  
For : IMPROVED LASER ALIGN SENSOR  
WITH SEQUENCING LIGHT  
SOURCES  
Docket No. : C34.12-0021

Group Art Unit: 2877  
Examiner:

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Respectfully submitted,

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FORM PTO-1449	Atty. Docket No.: C34.12-0021	Appl. No.: 09/767,199
 LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT	First Named Inventor:	
	David W. Duquette	
	Filing Date	Group Art:
	January 22, 2001	2877

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
	AA	4,615,093	10/07/86	Tews et al.	29	407
	AB	5,278,634	01/11/94	Skunes et al.	356	400
	AC	5,559,727	02/24/96	Deley et al.	364	559
	AD	5,871,391	02/16/99	Pryor	451	9
	AE	5,880,880	05/04/99	Archima	356	375
	AF	08/904,950	08/01/97	Bartunek et al.		Pending
	AG					

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
✓	AH	WO 99/62313	12/02/99	WIPO		(Abstract Only)
✓	AI	JP 9-210626	08/12/97	Japan		(Abstract Only)
✓	AJ	JP 9-246794	09/19/97	Japan		(Abstract Only)
✓	AK	JP 9-307298	11/28/97	Japan		X
✓	AL	JP 10-93298	04/10/98	Japan		(Abstract Only)
✓	AM	JP 10-148514	06/02/98	Japan		(Abstract Only)
✓	AN	JP 10-284890	10/23/98	Japan		(Abstract Only)
✓	AO	JP 11-251797	09/17/99	Japan		(Abstract Only)
✓	AP	JP 2000-31697	02/28/00	Japan		(Abstract Only)
✓	AQ	JP 2000-13400	05/12/00	Japan		(Abstract Only)

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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